

10. The Board of Directors shall have the authority to make any amendments to the Bylaws of the Corporation, subject to the approval of the stockholders.

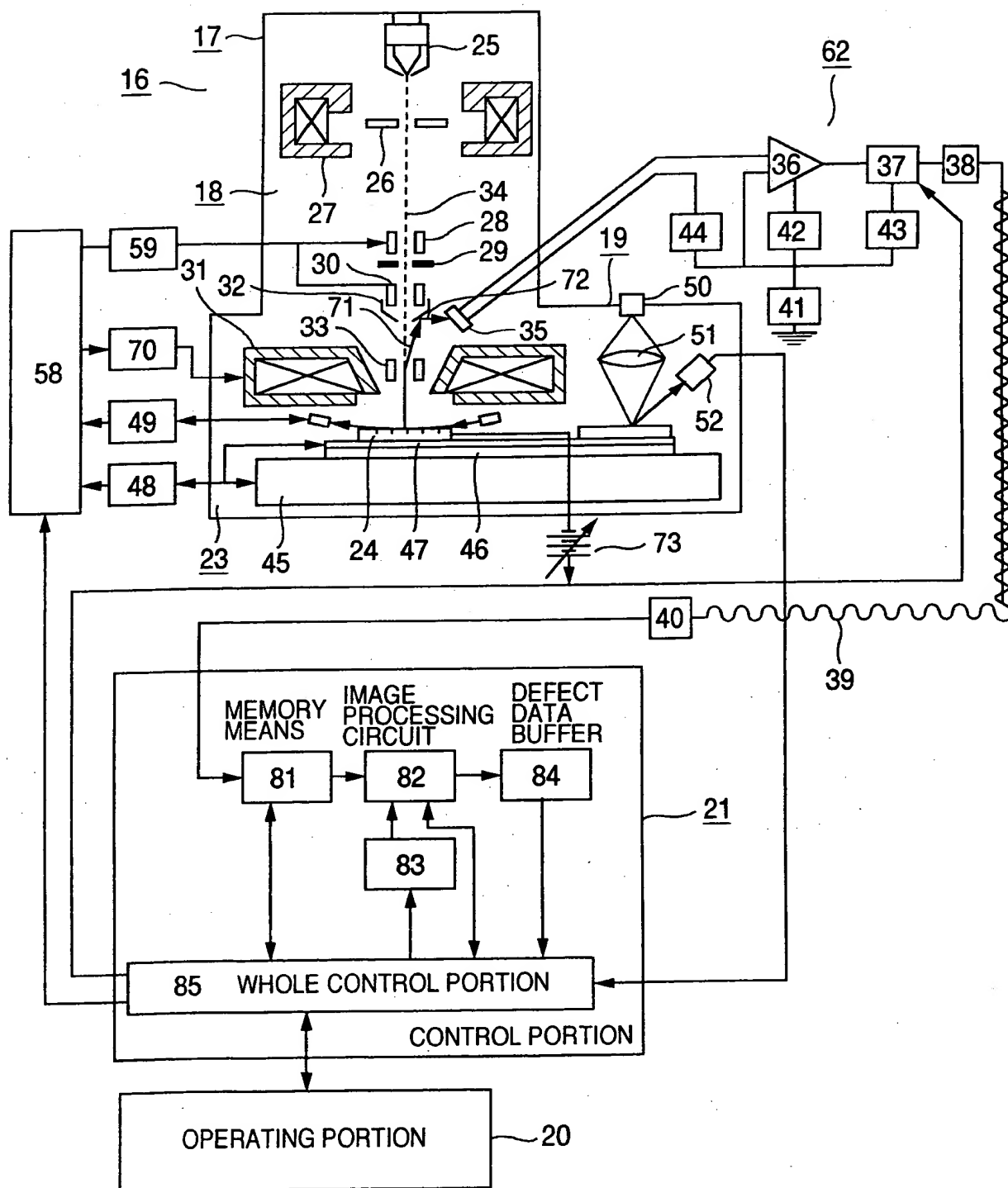


FIG.3

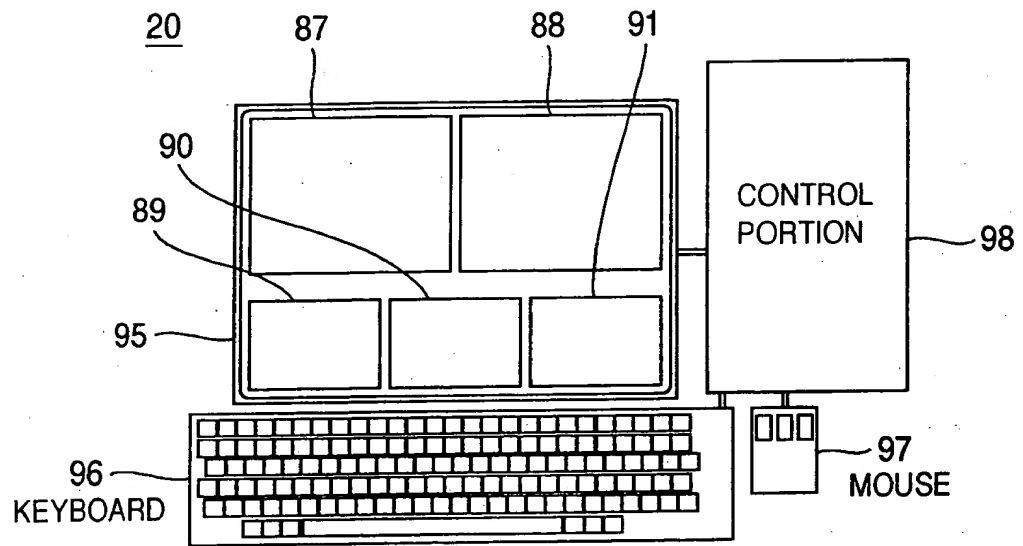


FIG.4

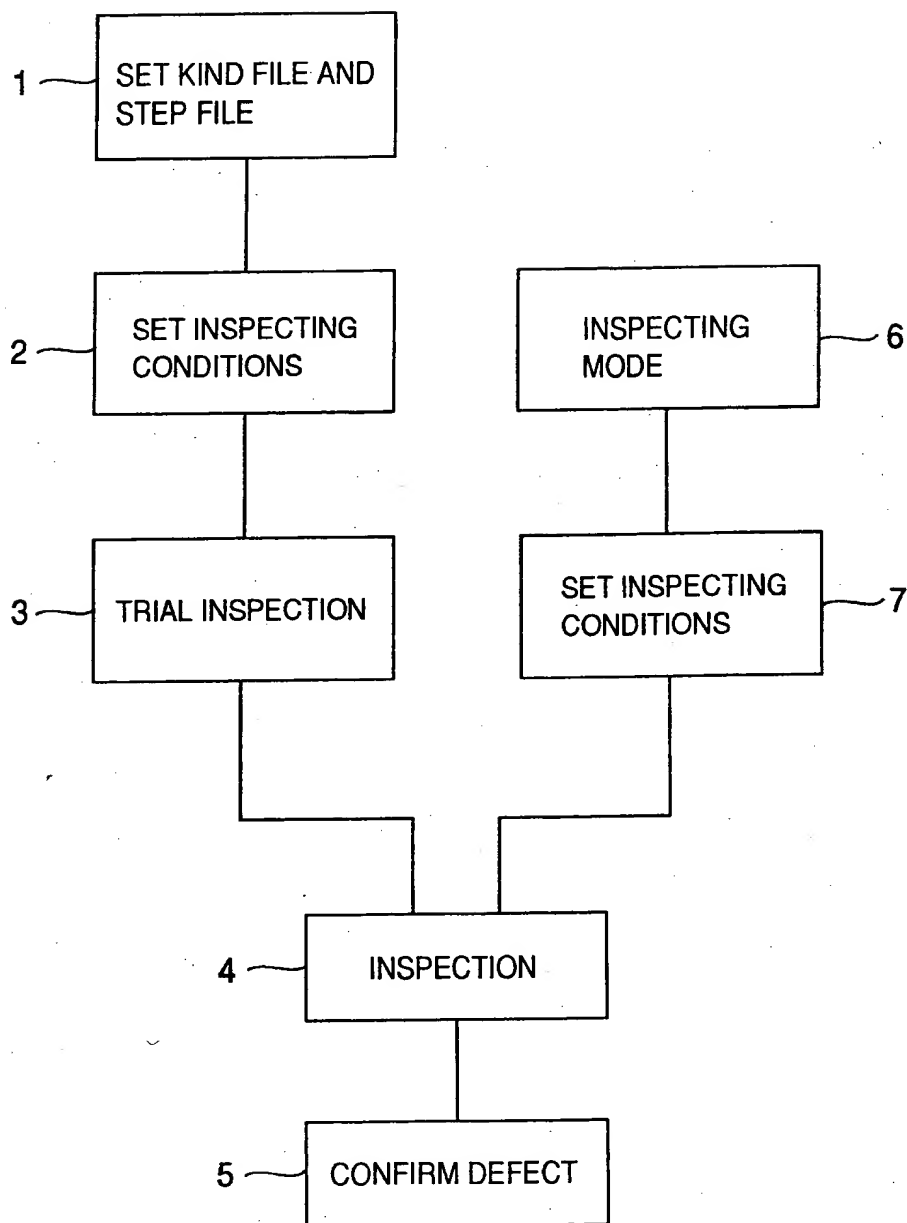


FIG.5

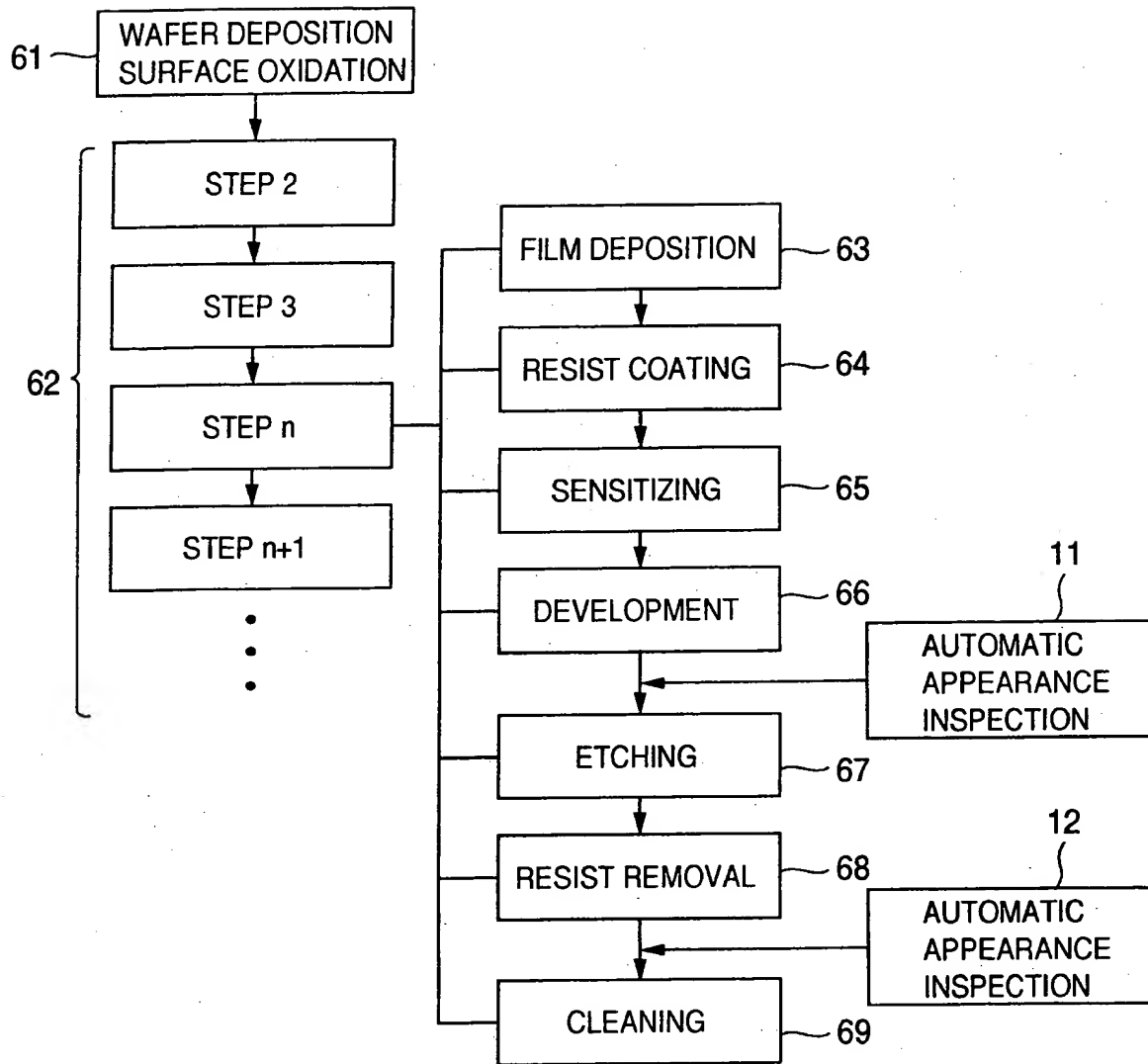


FIG. 6

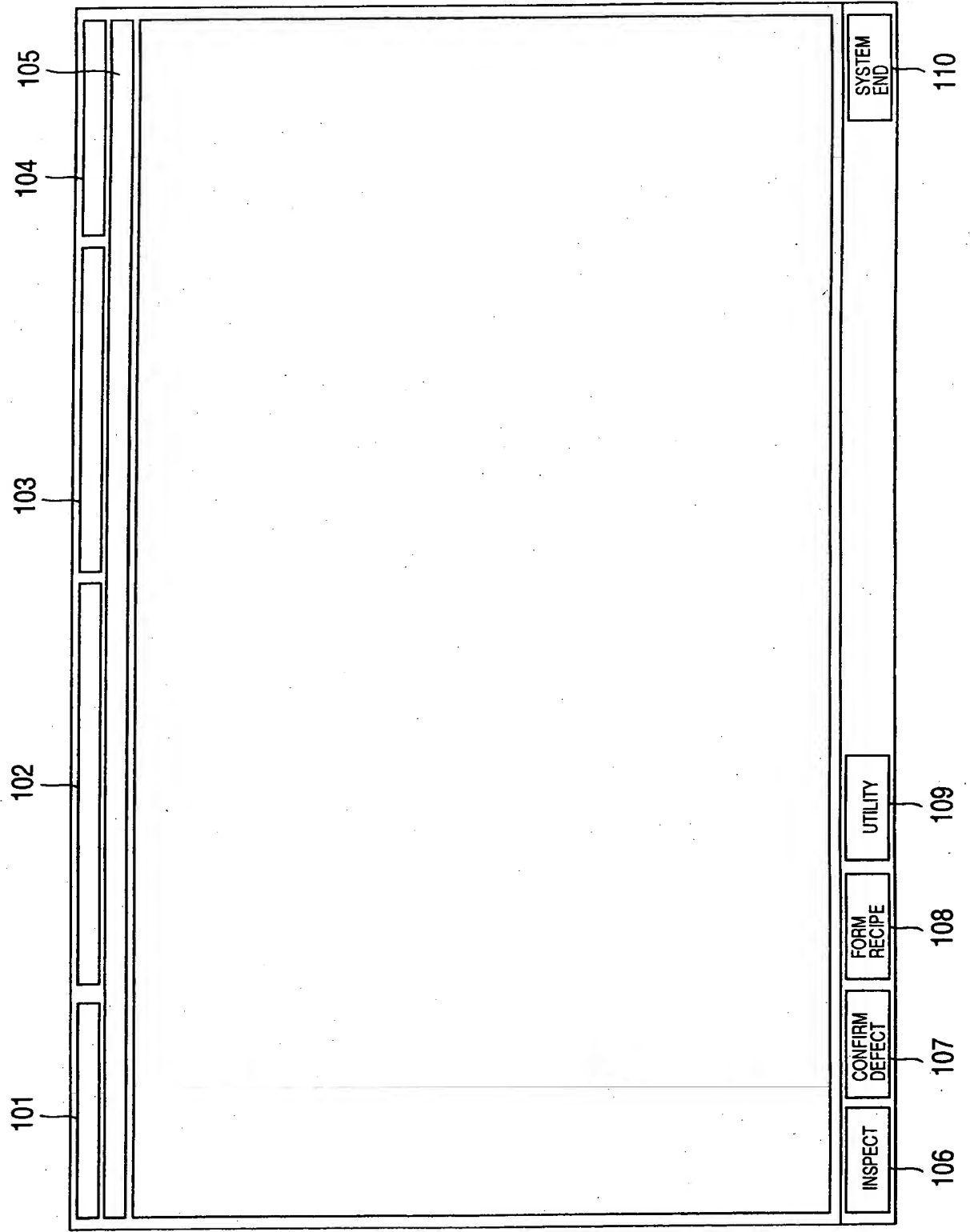


FIG.7

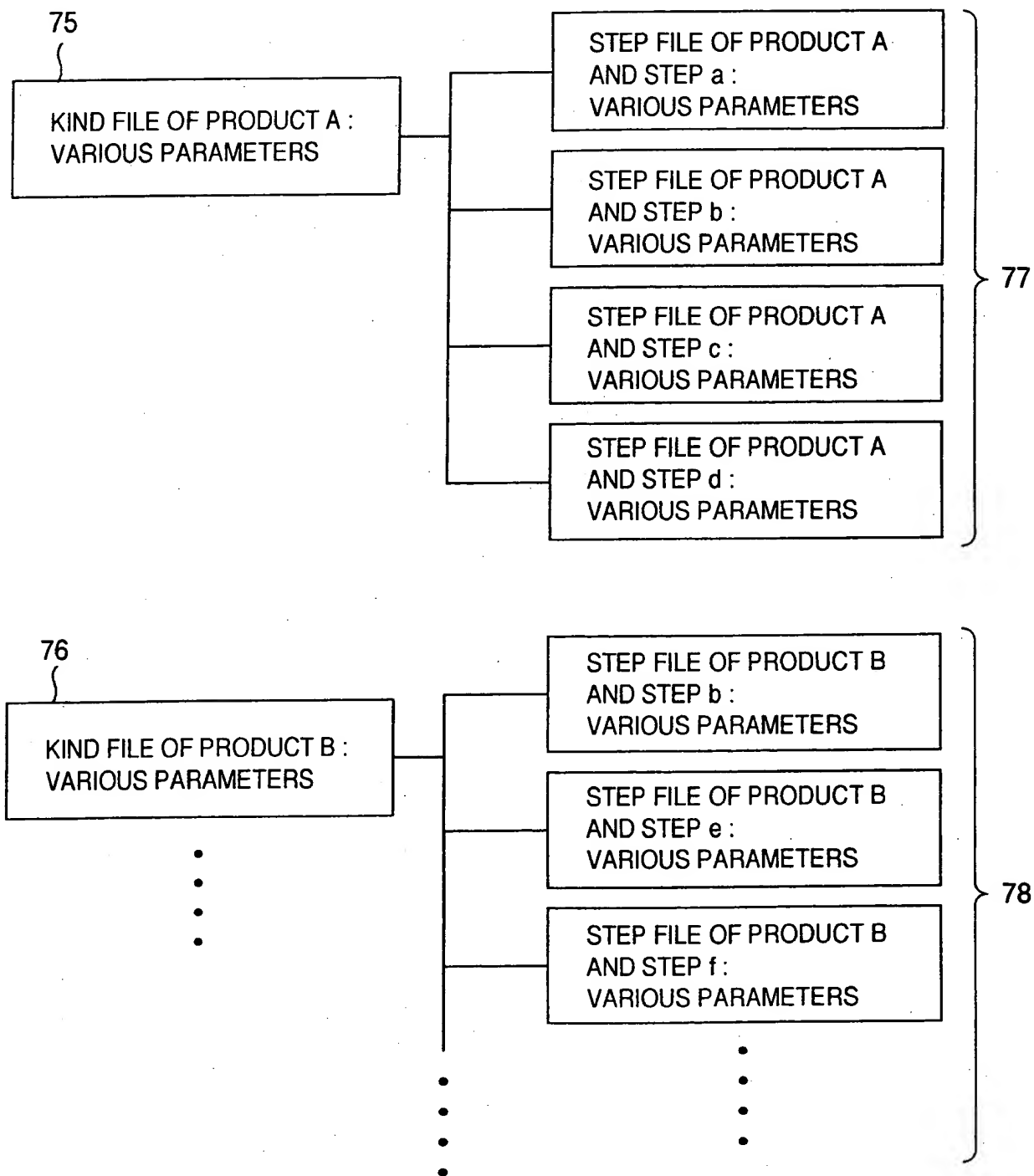


FIG.8

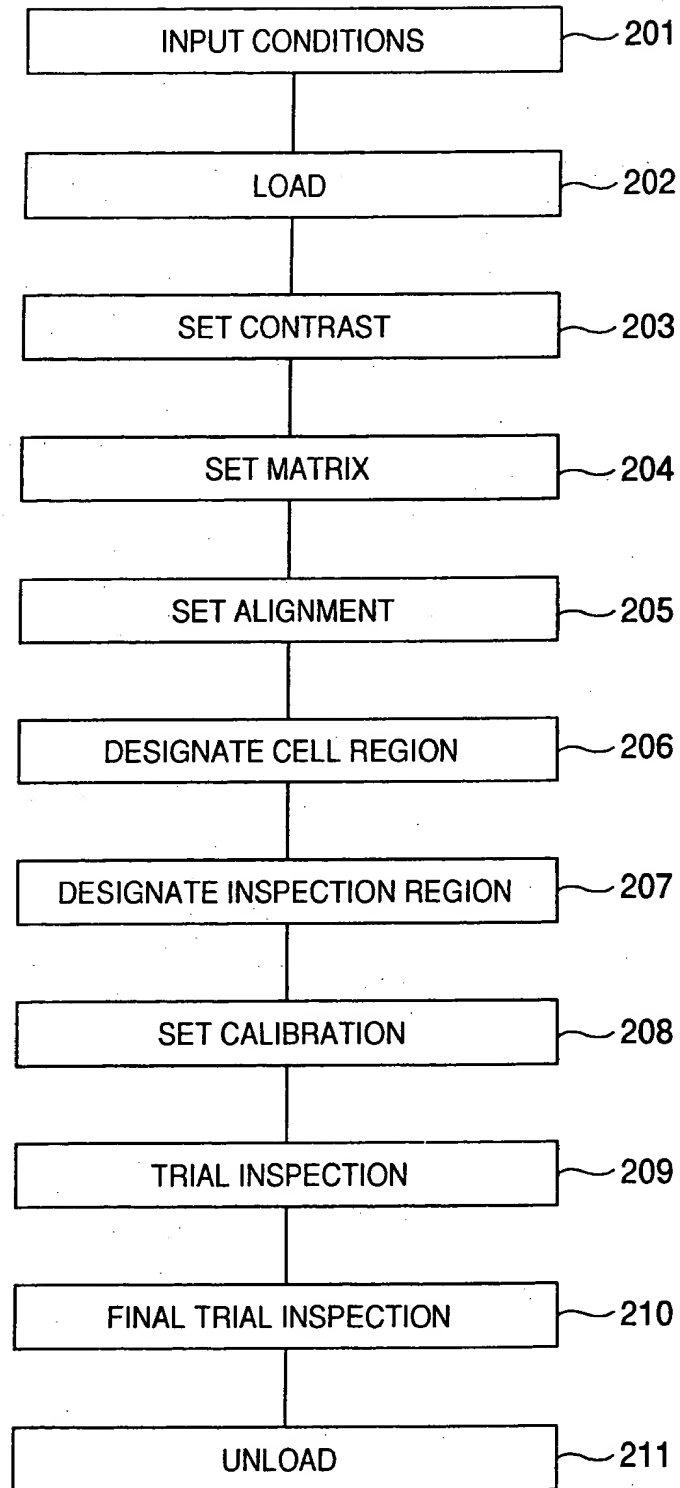


FIG.9

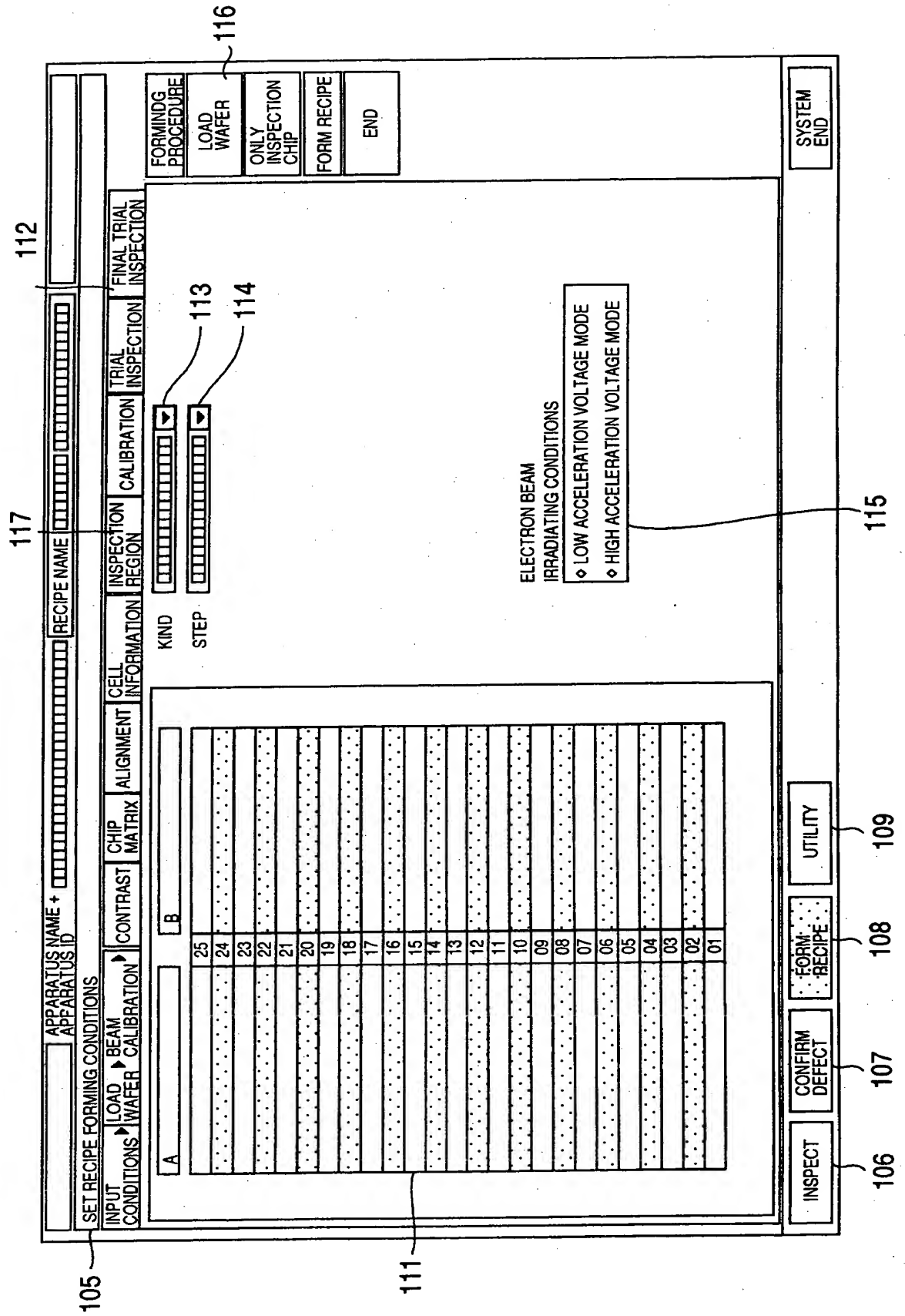


FIG. 10

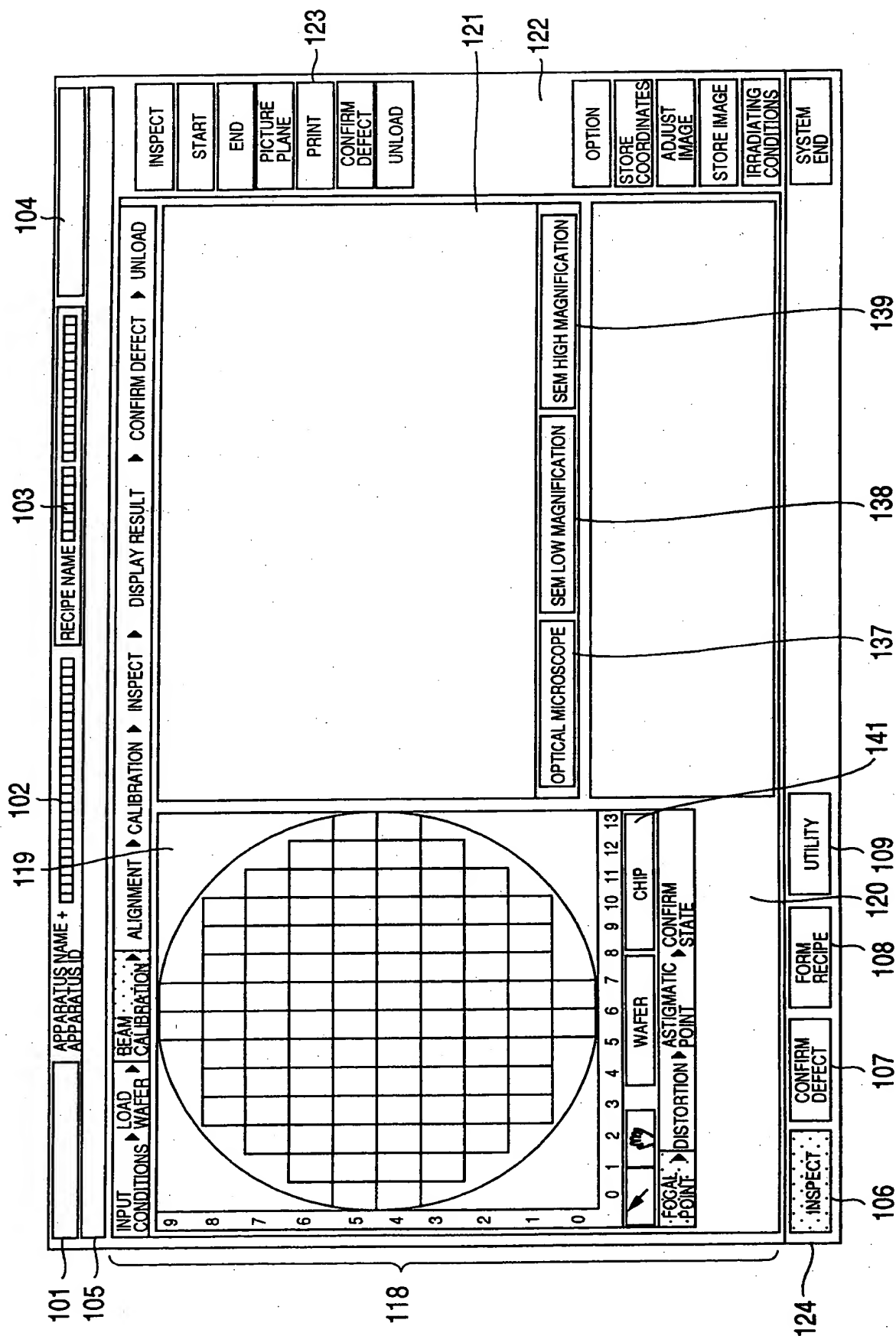


FIG.11

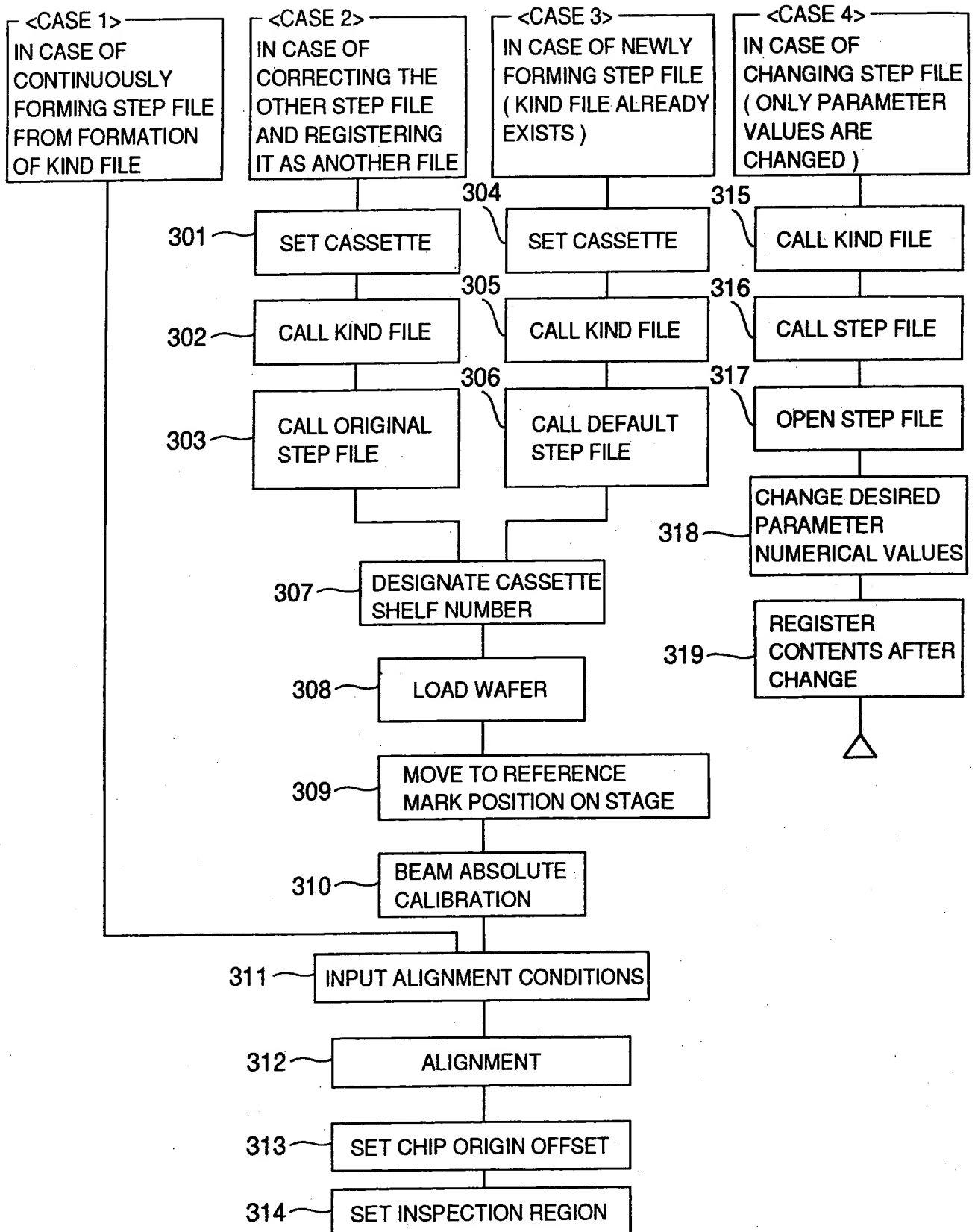


FIG.12

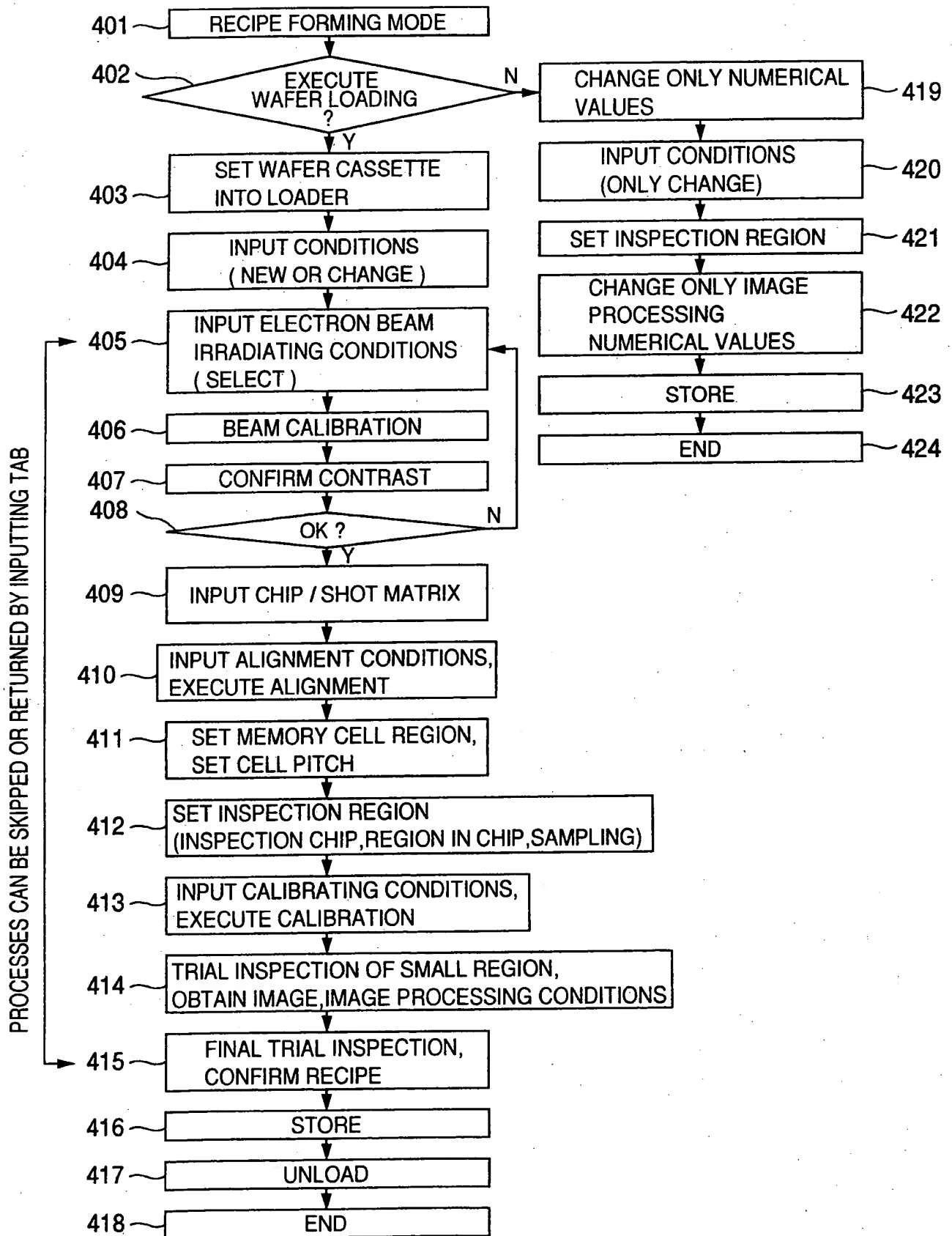


FIG. 13

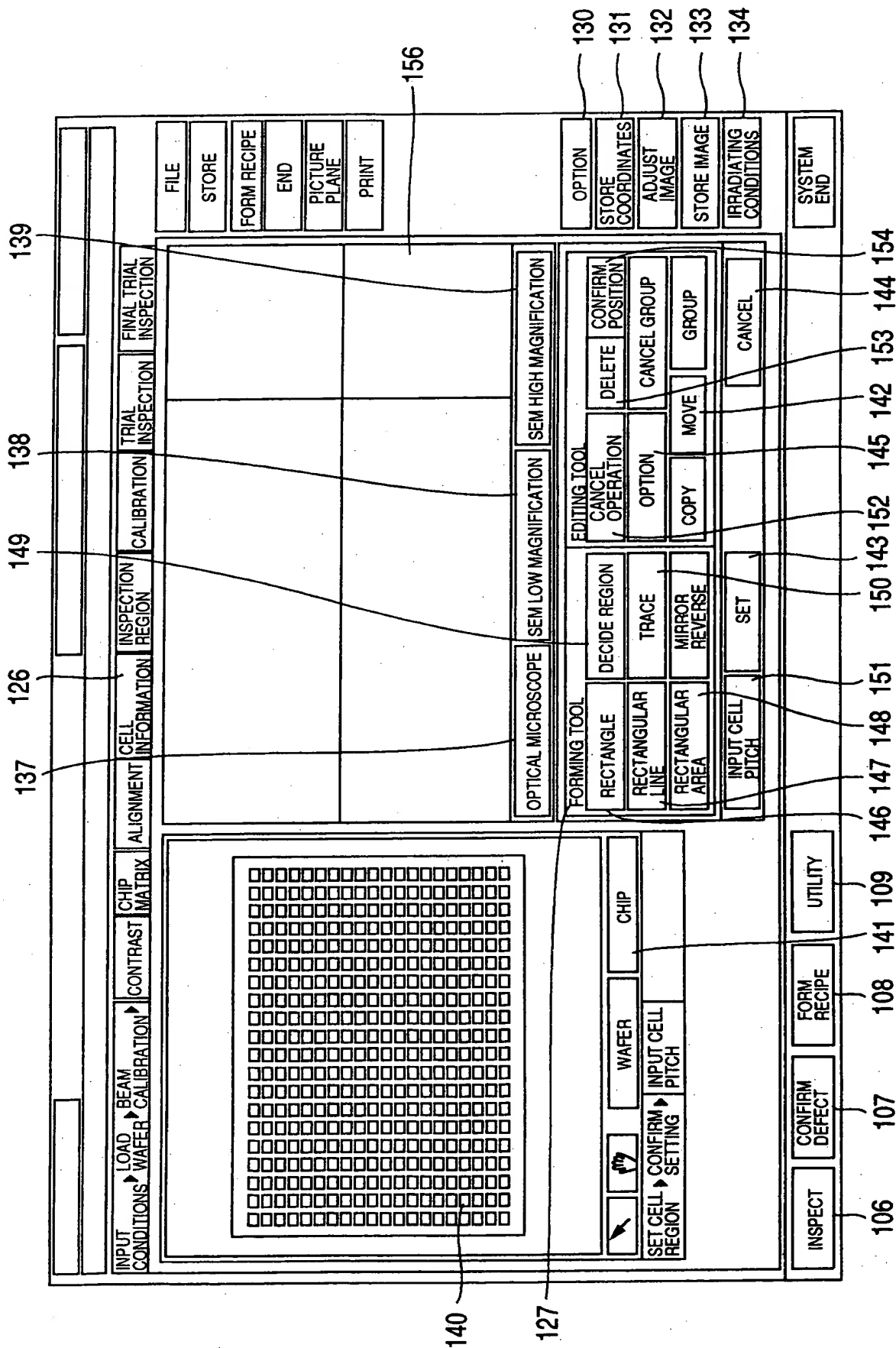


FIG.14

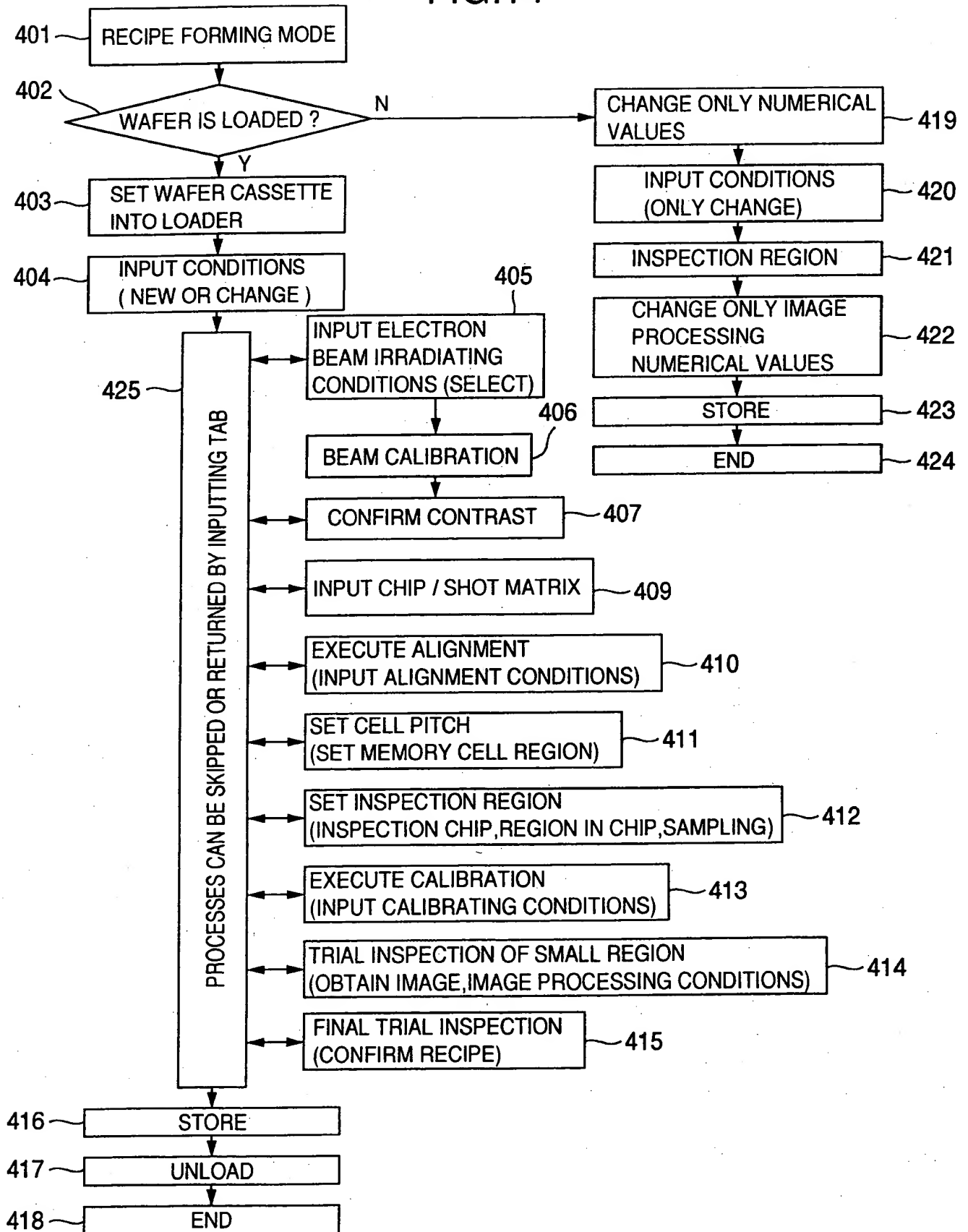


FIG.15

IRRADIATING CONDITIONS

ELECTRON BEAM IRRADIATING CONDITIONS

ACCELERATION VOLTAGE ▾ V

BEAM CURRENT ▾ nA

OBTAIN SIGNAL

THE NUMBER OF SIGNAL
ADDING TIMES ▾ ☐

PIXEL SIZE ▾ μm

SET CANCEL

92

93

94

FIG.16

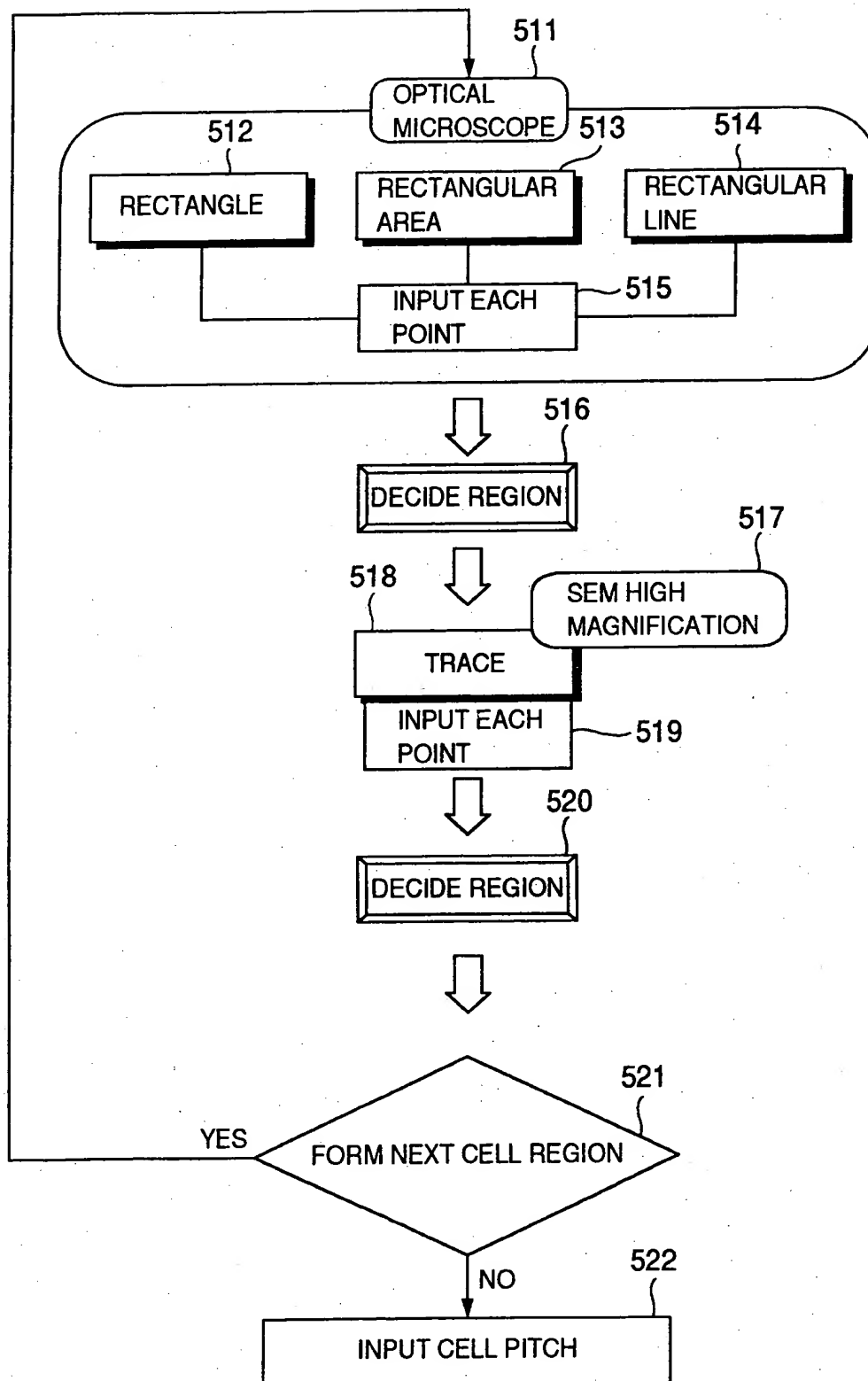


FIG.17

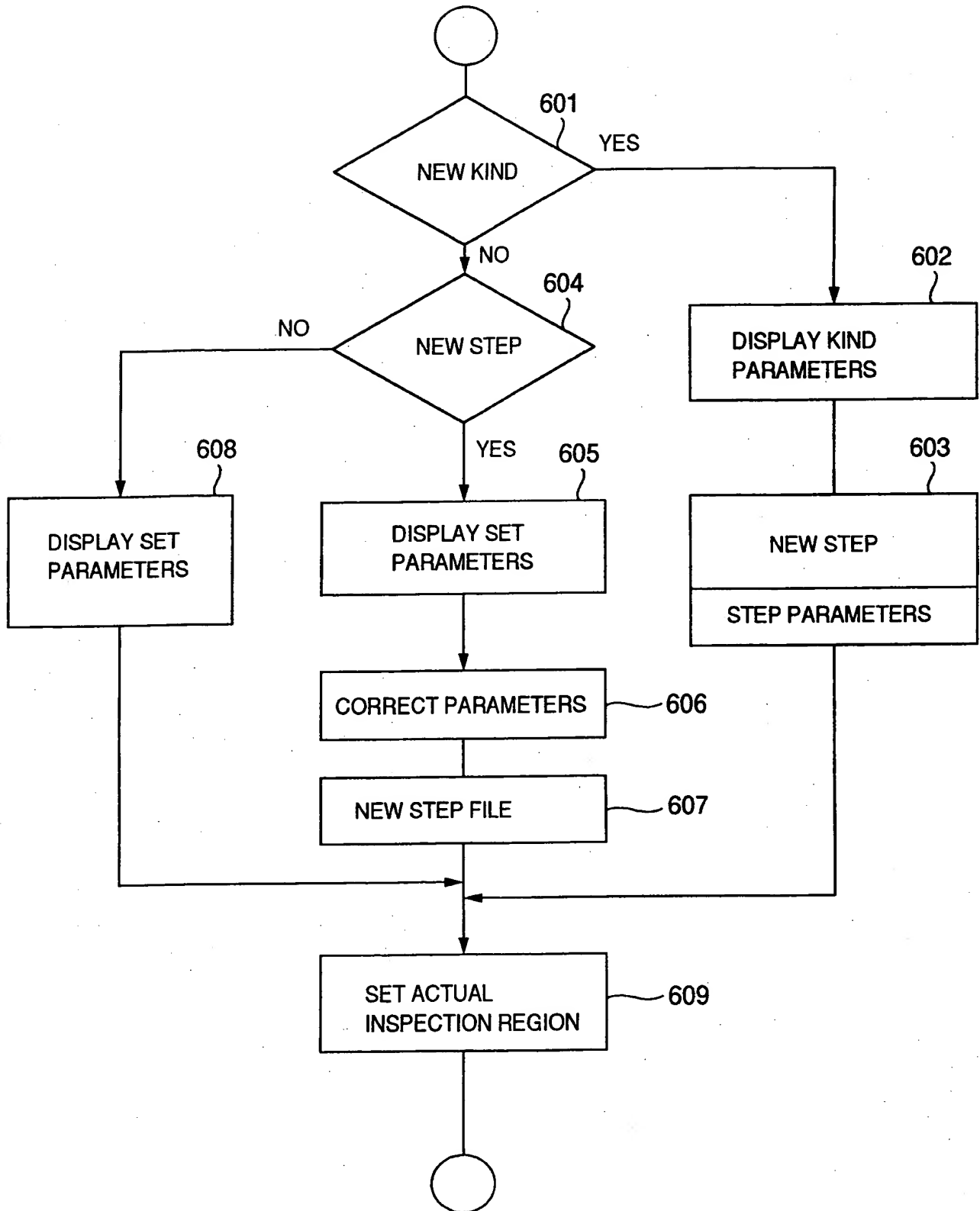


FIG.18

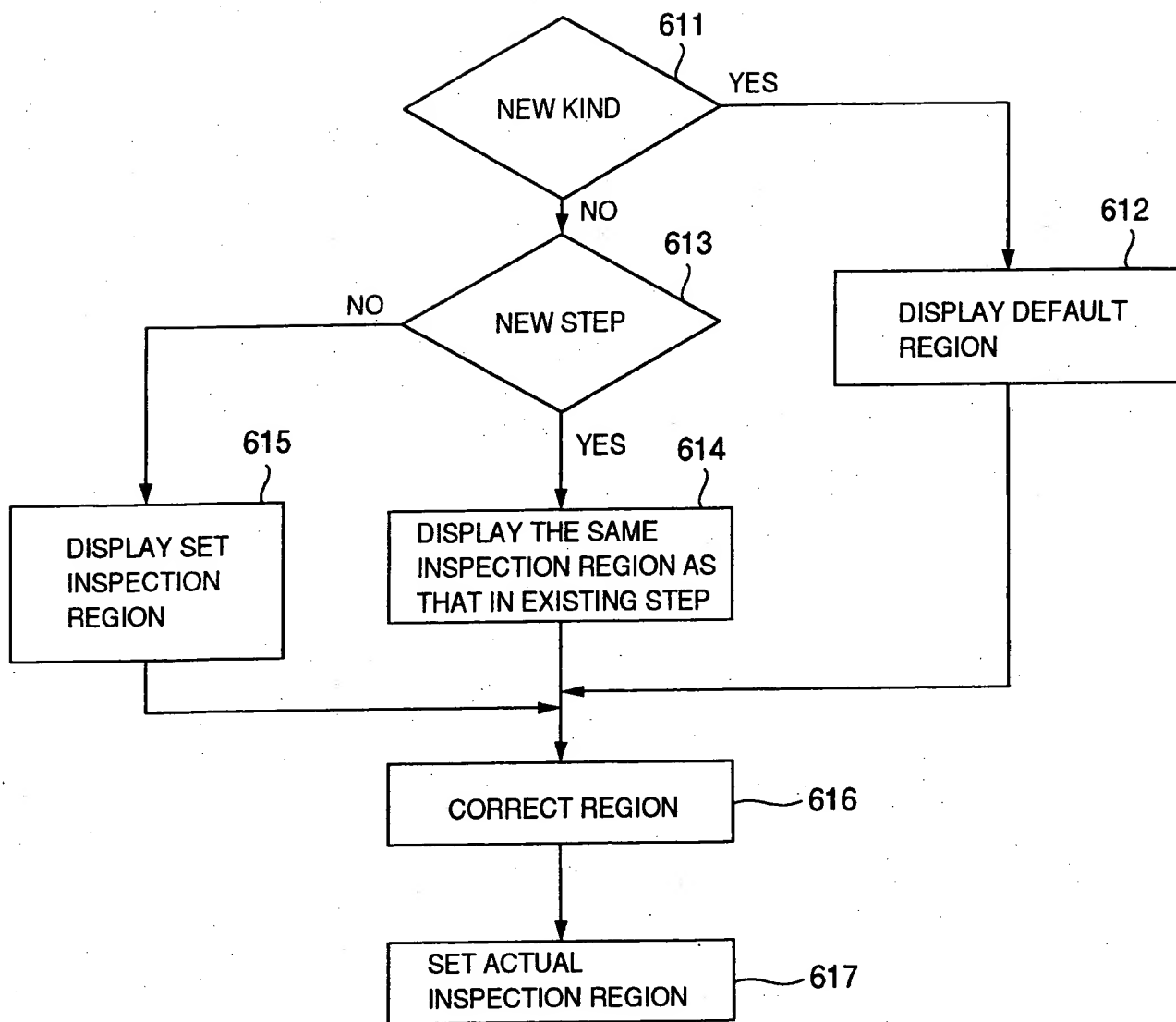


FIG.19

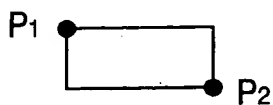


FIG. 20

FIG.20

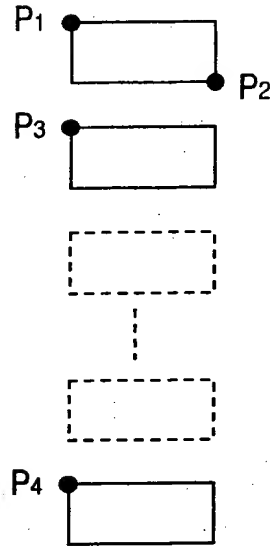


FIG.21

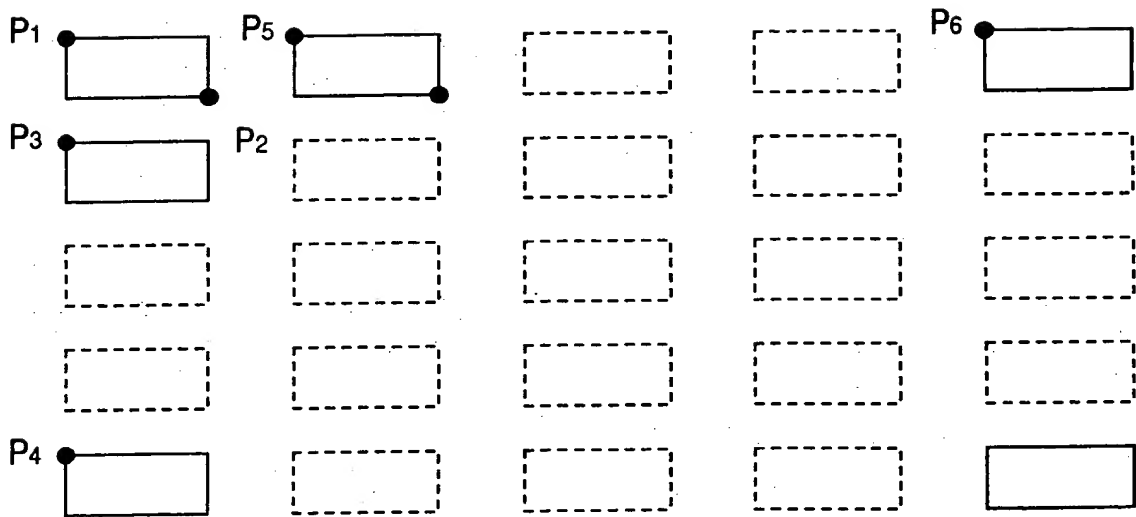


FIG.22

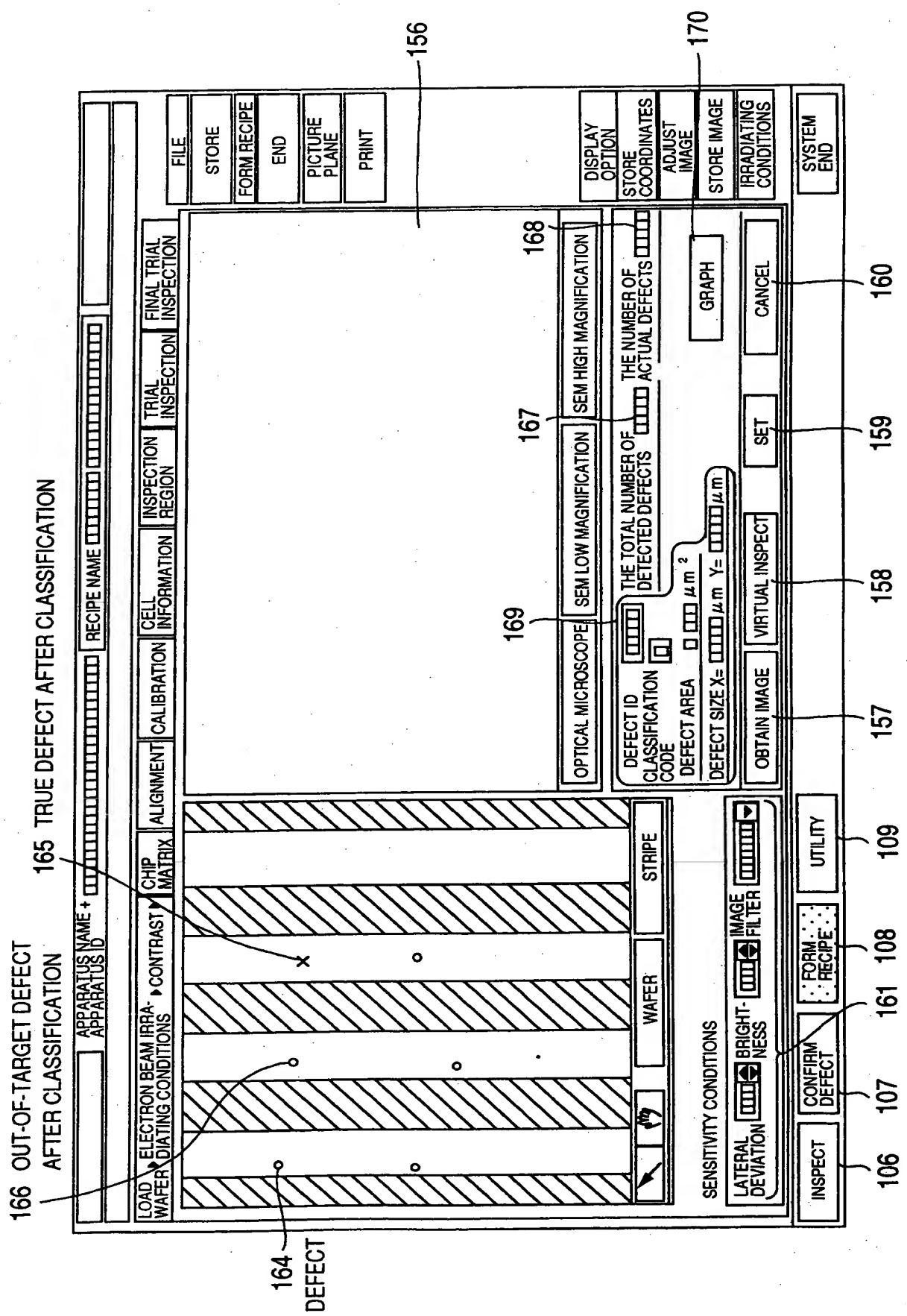


FIG. 23

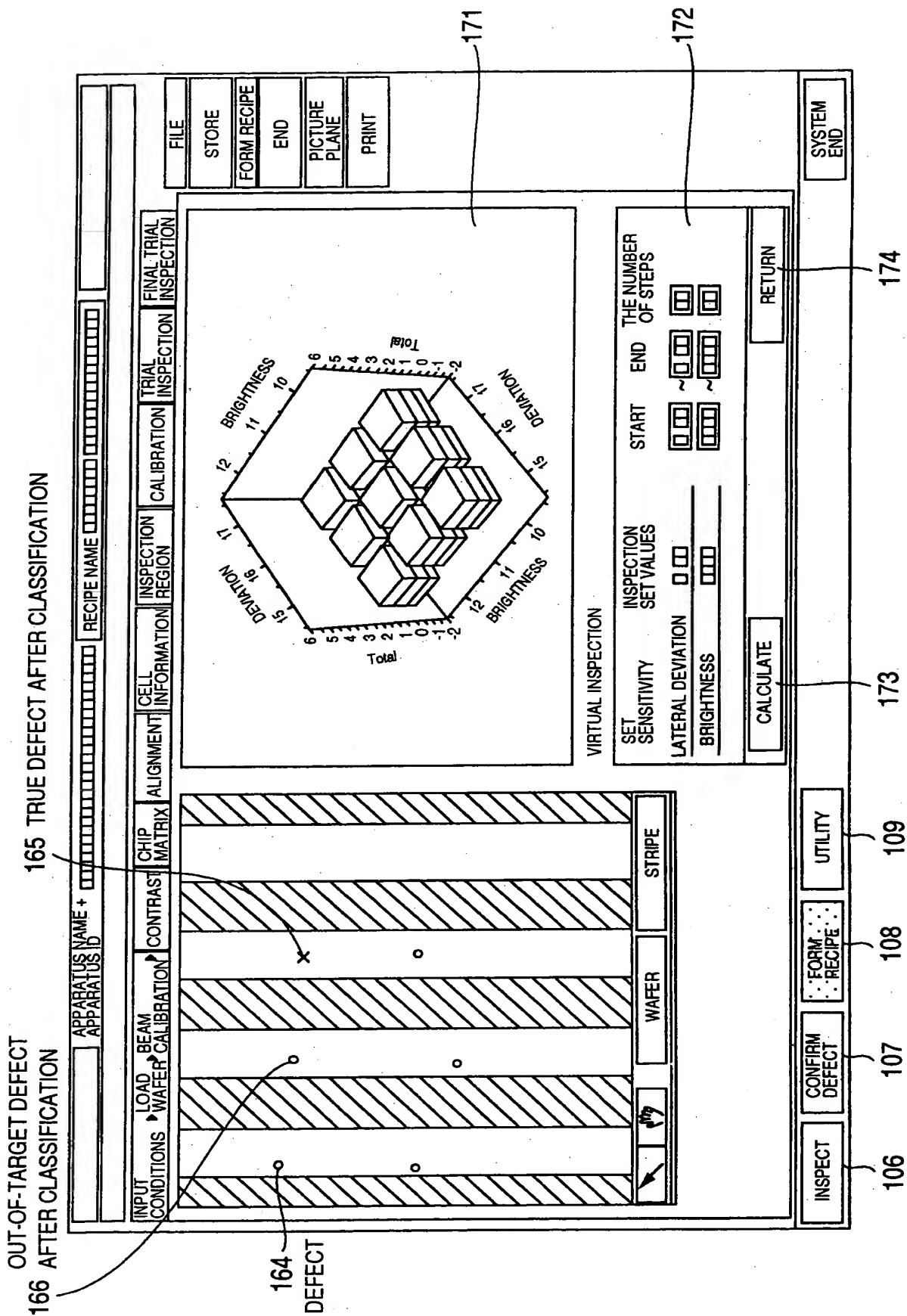
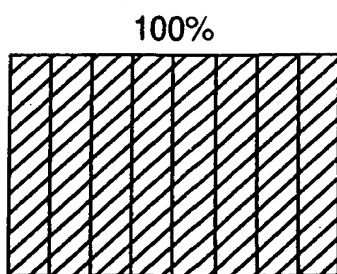
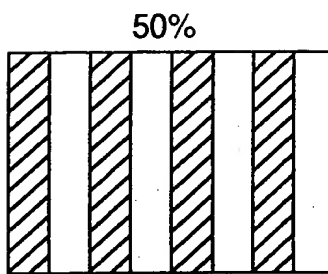


FIG.24A



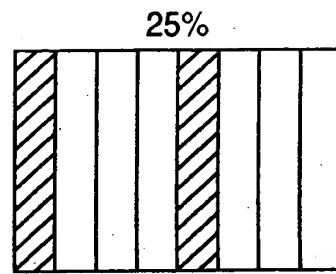
SCAN ALL
STRIPE

FIG.24B



SCAN EVERY
OTHER STRIPE

FIG.24C



SCAN EVERY
FOURTH STRIPE

FIG.25

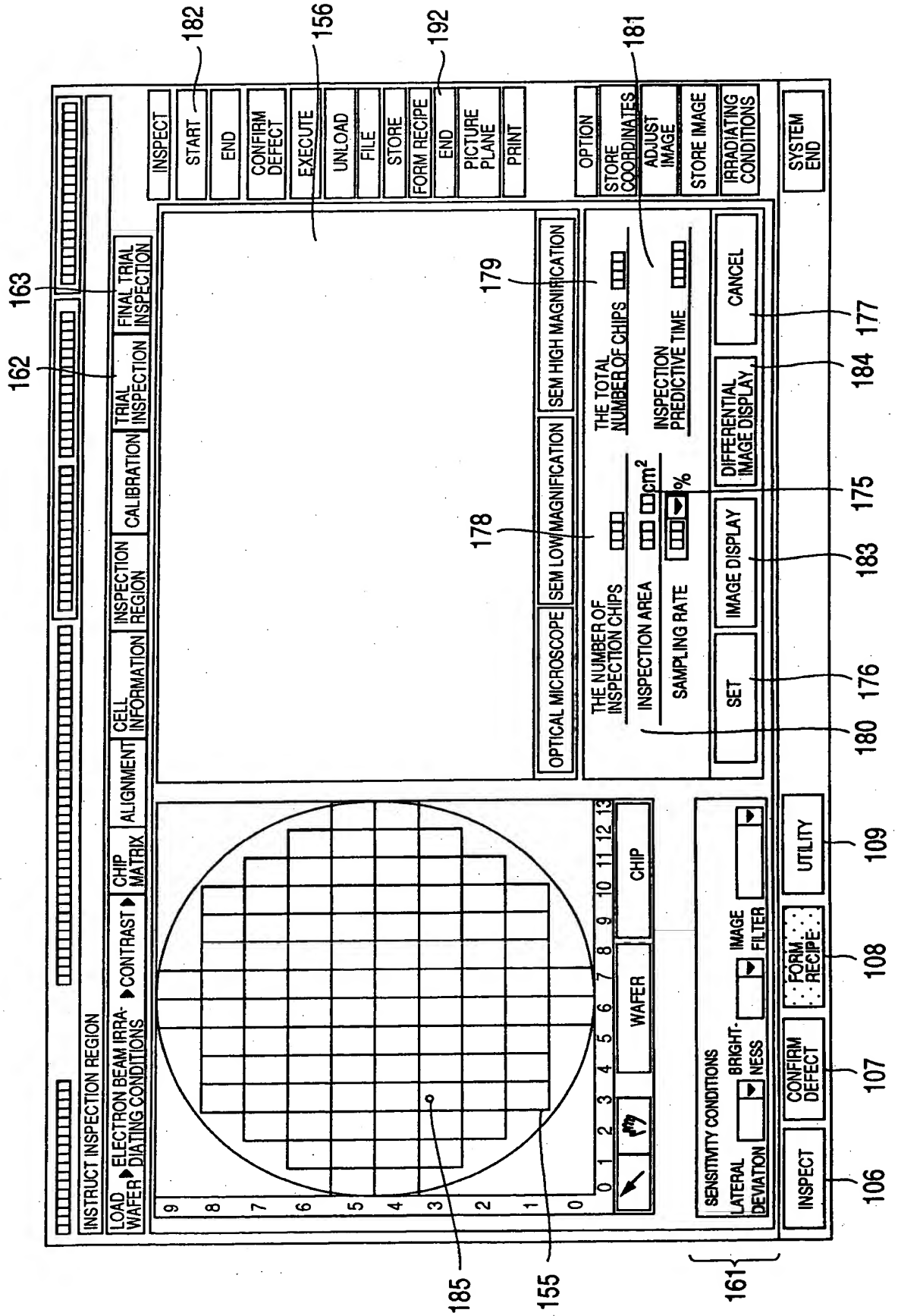


FIG.27

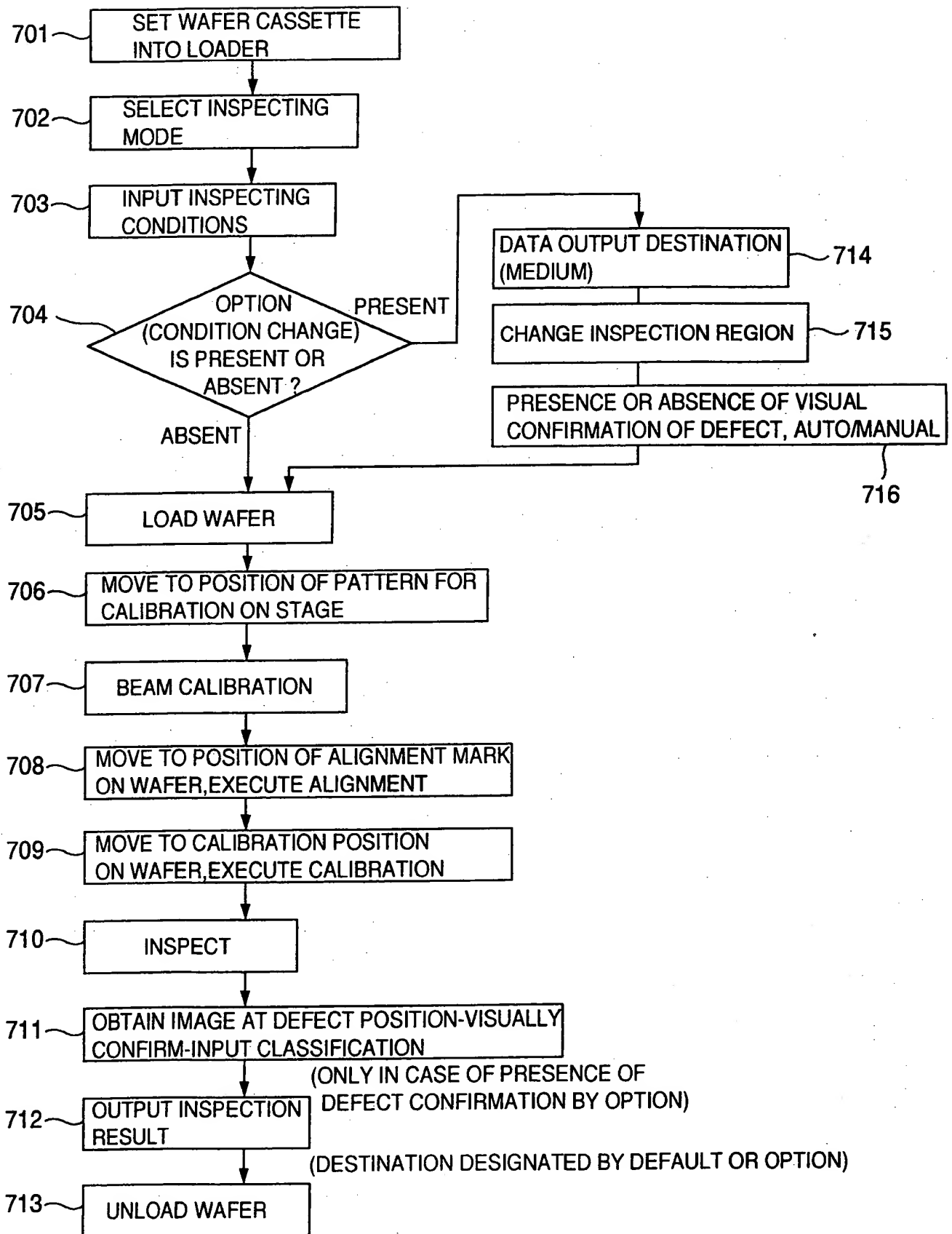


FIG. 29

105

INPUT
CONDITIONS

LOAD
WAFER

BEAM
CALIBRATION

ALIGNMENT
CALIBRATION

INSPECT
CONFIRM DEFECT

UNLOAD

INSPECT
START
END
PICTURE PLANE
PRINT

909

PROGRESS OF INSPECTION

THE NUMBER OF DEFECTS 216

THE NUMBER OF DEFECTIVE CHIPS 54

DEFECT DENSITY 3.021

FAILURE CHIP RATE 100.00 %

INSPECTION TIME

INSPECTION END TIME

910

SHELF NUMBER B15

KIND HQJ1

STEP Holipro

WAFER ID 22 LOT ID 11

OPERATOR BORIOKA.HIROSIII

COMMENT print

106

INSPECT

107

CONFIRM DEFECT

108

FORM RECIPE

109

UTILITY

FIG. 30

Figure 1 is a schematic diagram of a control interface for a wafer inspection system. The interface is organized into several key sections:

- Top Section:** Includes input fields for "APPARATUS NAME + APPARATUS ID" and "RECIPE NAME", followed by a "SET INSPECTING CONDITIONS" button.
- Menu Bar:** A horizontal bar containing the following options: "INPUT CONDITIONS", "LOAD BEAM", "WAFER CALIBRATION", "ALIGNMENT", "CALIBRATION", "INSPECT", "DISPLAY RESULT", "CONFIRM DEFECT", and "UNLOAD".
- Main Display Area:**
 - Left Pane (916):** Contains a "CHANGE OPERATING CONDITIONS" section with a "CONFIRM OPERATION" button and a list of conditions (MANUAL, AUTO, NOT DONE) with selection arrows. Below this is a "SET" button.
 - Right Pane (917):** Contains a "CHANGE INSPECTION REGION" section with a "CHANGE RESULT OUTPUT DESTINATION" button and a "CHANGE OPERATING CONDITIONS" button.
- Grid (111):** A large grid with 17 rows and 17 columns, labeled with numbers 01 to 17. To the right of the grid is a "NEW" button.
- Bottom Section:** Includes fields for "LOT ID", "WAFER ID", "OPERATOR'S NAME", "COMMENT", and "OPTION".
- Footer:** A row of buttons at the bottom: "INSPECT", "CONFIRM DEFECT", "FORM RECIPE", "UTILITY", and "SYSTEM END".

FIG.31

918

APPARATUS NAME + APPARATUS ID

RECIPE NAME

SET INSPECTING CONDITIONS

INPUT CONDITIONS ▶ LOAD ▶ BEAM CALIBRATION ▶ WAFER CALIBRATION ▶ ALIGNMENT ▶ CALIBRATION ▶ INSPECT ▶ DISPLAY RESULT ▶ CONFIRM DEFECT ▶ UNLOAD

CHANGE RESULT OUTPUT DESTINATION

SHELF NUMBER

— J H/D

— J F/D

— J MO

— J AS

— J PRINTER

◆ STANDARD

> OPTION

SET

CANCEL

B

LOT ID

WAFER ID

OPERATOR NAME

COMMENT

OPTION

SHELF NUMBER

KIND

STEP

NEW

INSPECT

START

END

PICTURE PLANE

PRINT

CHANGE INSPECTION REGION

CHANGE RESULT OUTPUT DESTINATION

CHANGE OPERATING CONDITIONS

11

10

09

08

07

06

05

04

03

02

01

INSPECT

CONFIRM DEFECT

FORM RECIPE

UTILITY

SYSTEM END

907

919

920

106

107

108

109

FIG.33

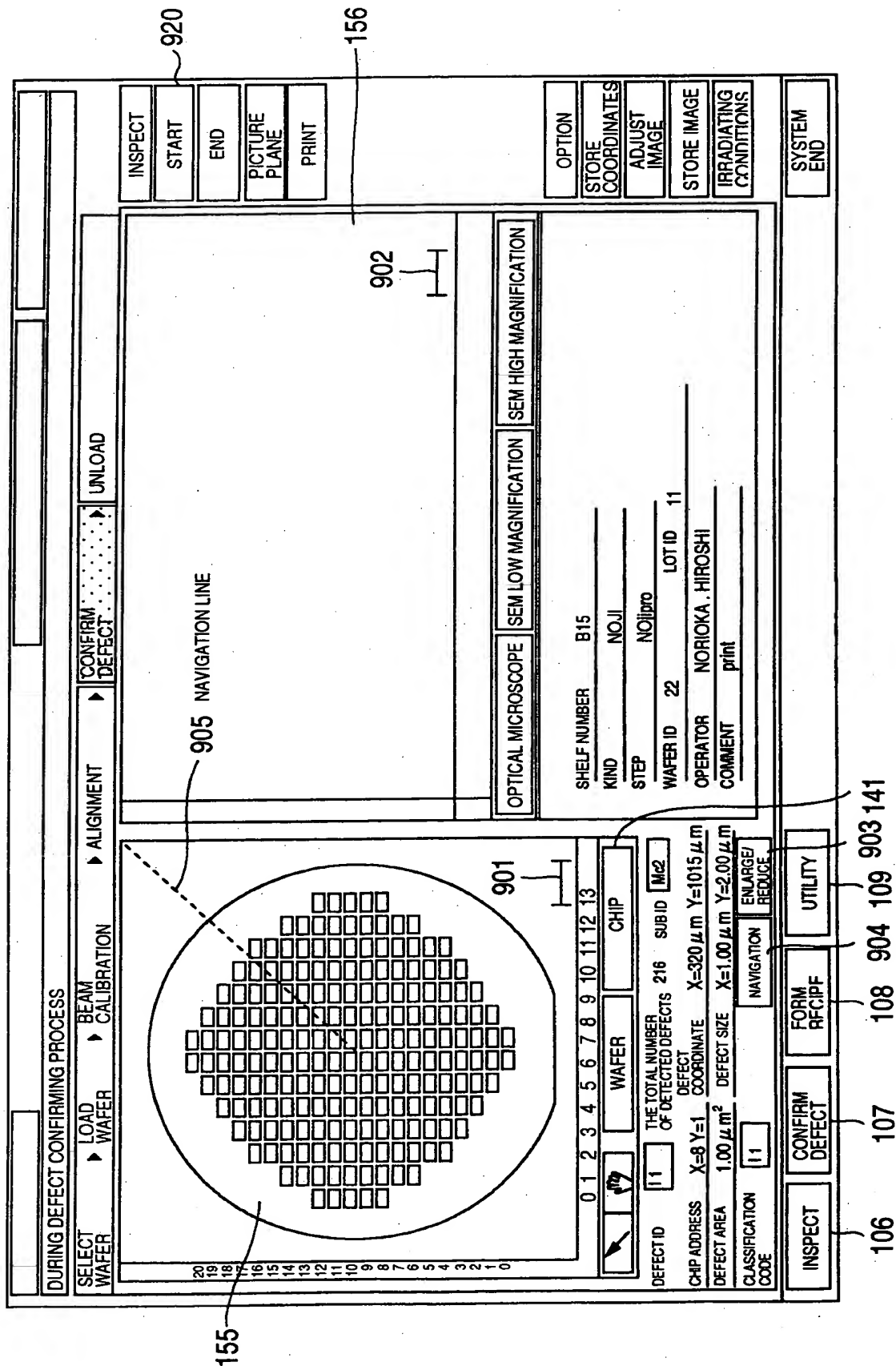


FIG.34

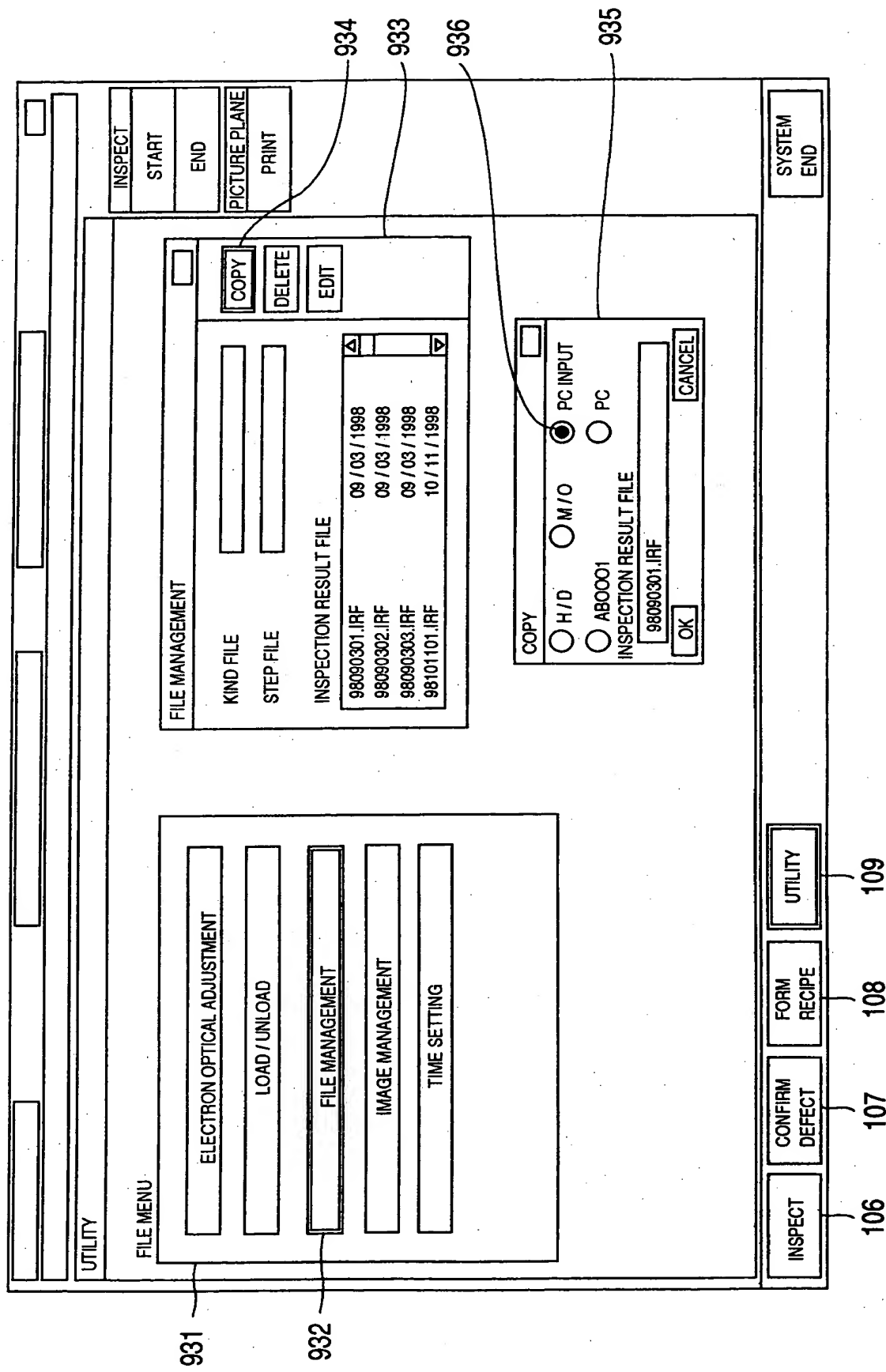


FIG.35

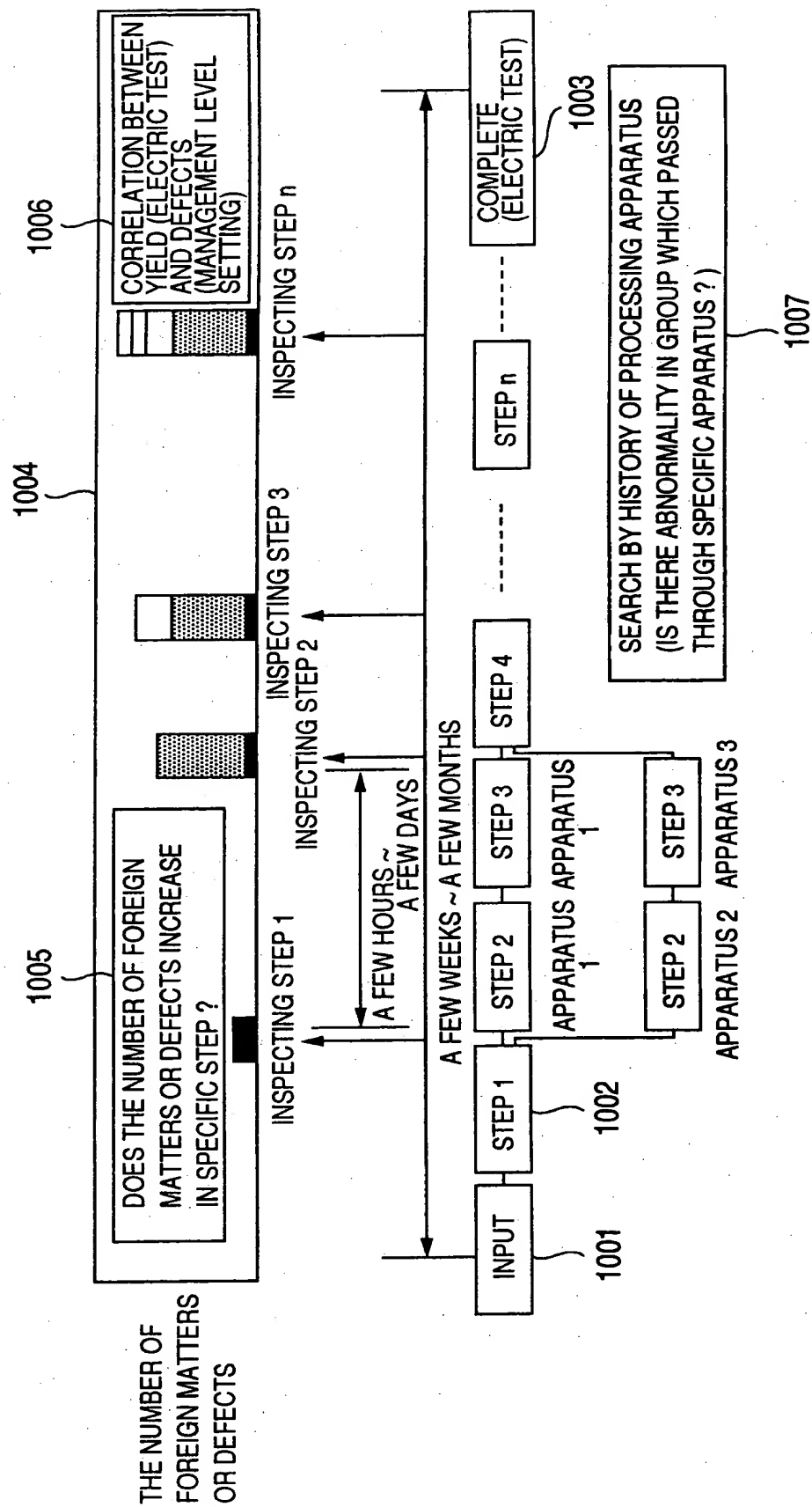


FIG. 37

